



Applied Physics, Inc.

400 N County Road 2E
Monte Vista, CO 81144 USA

Nano Particle Technology

Cel 1-720-635-3931
Email Sales@AppliedPhysicsUSA.com
Web www.AppliedPhysicsUSA.com

Particle Contamination Wafer Standard: 32nm to 5.00µm

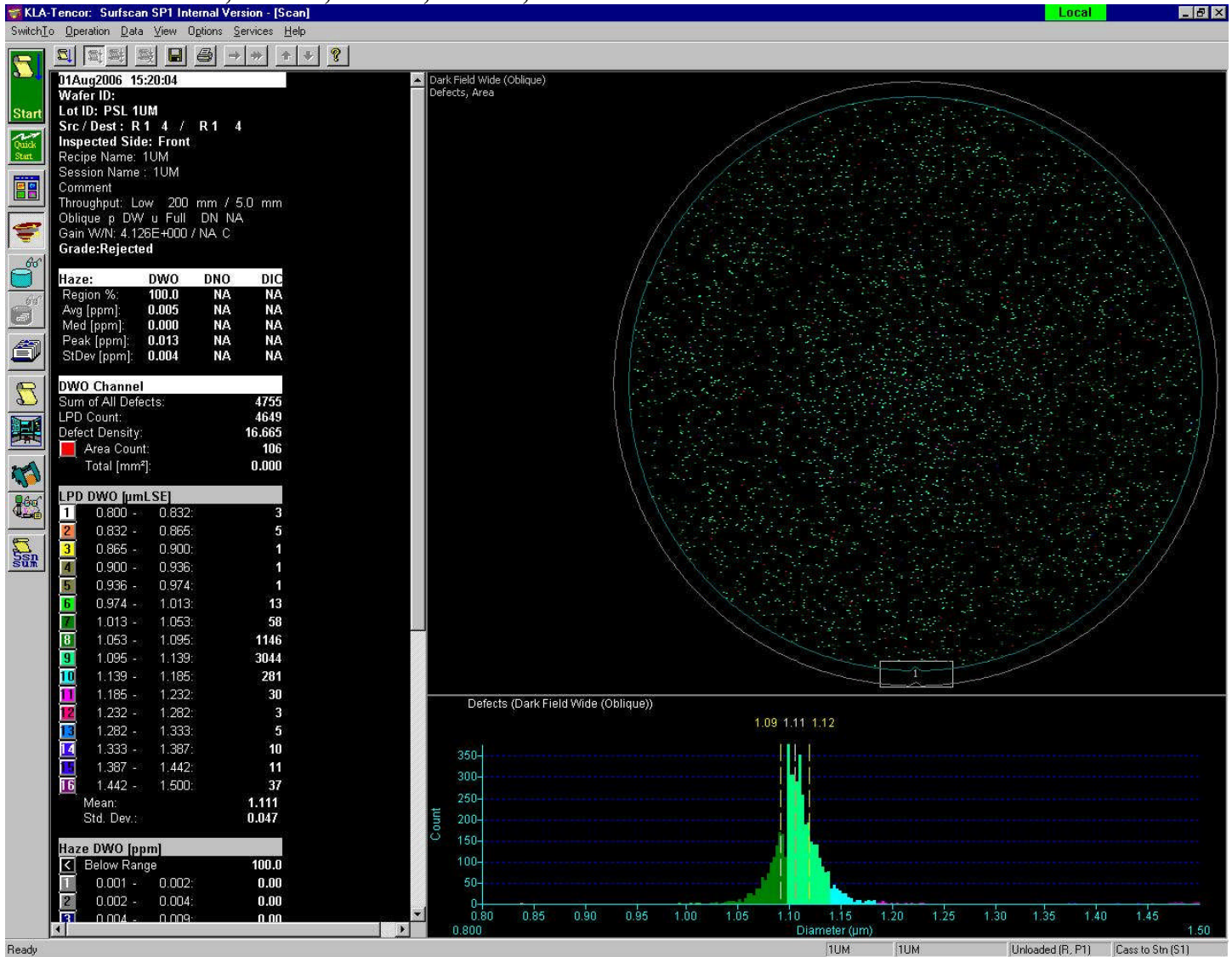
Silica Particles

Spot Depositions from 50nm to 2.0µm

Full Depositions from 50nm to 2.0µm

NIST Traceable, Particle Wafer Size Standards and FILM Size Standards

100mm, 150mm, 150mm, 200mm, 300mm Prime Silicon Wafers and FILM Wafers



1µm deposited on Calibration Wafer, SP1 Response shows 1.11µm, SP1 Requires Calibration

Particle Calibration Wafer Standards:

- 1) NIST Traceable Particle Size Certificate based on NIST SRM calibration: 60.4nm, 101.8nm, 269nm, 895nm
- 2) Size Calibration of KLA-Tencor SP1, KLA-Tencor SP2, KLA Tencor SP3, SP5, SPx, Tencor 6420
- 3) Packaged in Single Wafer Carriers, bagged for shipping cleanliness
- 4) Each wafer standard, Single Wafer Carrier is labeled with deposition specifications
- 5) Post Wafer Scan using color printout; Particle Size Certificate provided to certify size accuracy

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Bill To: PO Box 186, Monte Vista, CO 81144 USA Ship To: 400 N County Road 2E, Monte Vista, CO 81144 USA

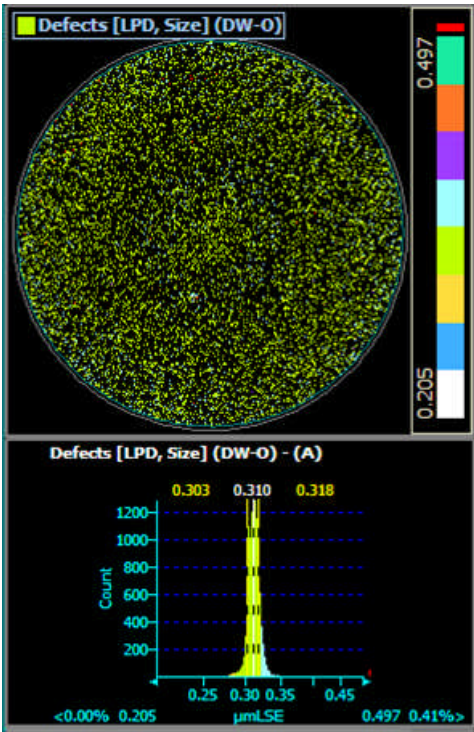


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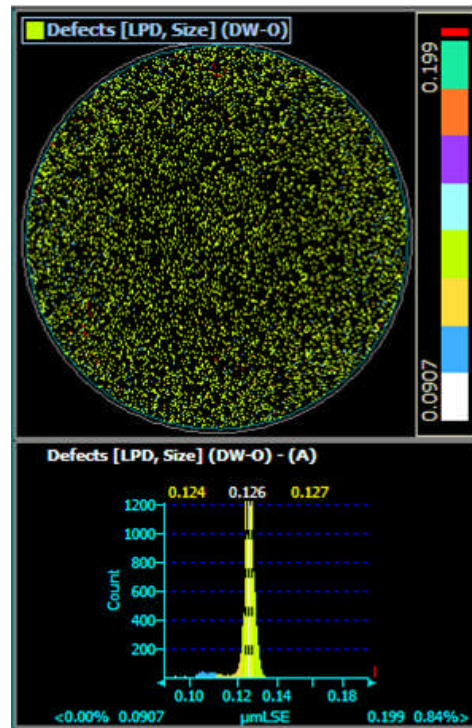
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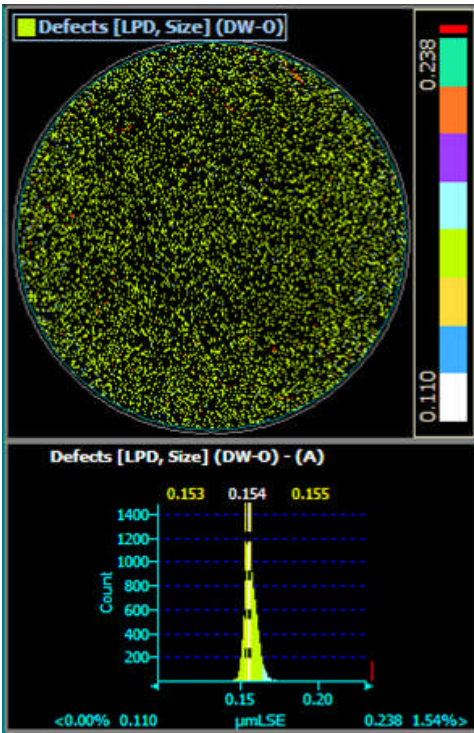


SSIS calibration check at 304nm

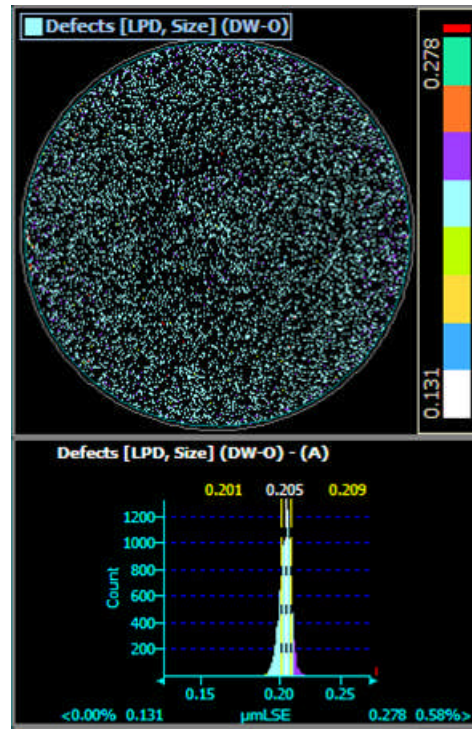


SSIS calibration check at 126nm

SPOT DEPOSITION or FULL WAFER DEPOSITION



SSIS calibration check at 155nm



SSIS calibration check @ 204nm

SPOT DEPOSITION or FULL WAFER DEPOSITION

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